

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent No. 7183220B1
Patent Issue Date February 27, 2007
Application Serial No. 09677478
Filing Date August 27, 1998
Assignee Micron Technology, Inc.
Inventorship Blalock, Guy T.
Attorney's Docket No. MI22-1544
Title: Plasma Etching Methods

REQUEST FOR CERTIFICATE OF CORRECTION OF PATENT
FOR PTO MISTAKE (37 C.F.R. 1.322(a))

To: Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450
ATTN: Decision and Certificate of Correction
Branch of the Patent Issue Division

From: D. Brent Kenady (Tel. 509-624-4276; Fax 509-838-3424)
Wells St. John P.S.
601 W. First Avenue, Suite 1300
Spokane, WA 99201-3828

Sir/Madam:

It is hereby requested that a Certificate of Correction be issued with respect to Patent No. 7183220B1, granted February 27, 2007, in accordance with the Certificate of Correction form attached hereto.

The errors listed on the Certificate of Correction form were apparently incurred through the fault of the PTO as will be disclosed by the records of files in the Office.

Please find attached a copy of the Supplemental Information Disclosure Statement filed October 19, 2001. The Form PTO-1449 was

initialed and signed by the Examiner on March 15, 2002. However, items AC, AD, and AE listed on the Form PTO-1449 were not listed in the issued patent; therefore, Applicant respectfully requests these references be listed in the issued patent.

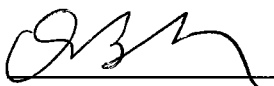
Please find attached a copy of the Supplemental Information Disclosure Statement filed December 30, 2002. The Form PTO-1449 was initialed and signed by the Examiner March 14, 2003. However, the items listed on Form PTO-1449 were not listed in the issued patent; therefore, Applicant respectfully requests these references be listed in the issued patent.

Attached hereto is Form PTO-1050, which is suitable for printing.

Since this Certificate of Correction is being requested due to PTO errors, it is believed that no fee is due. However, in the event that a fee is required for issuance of this Certificate of Correction, please charge the fee, any underpayment or credit any overpayment specified under 37 C.F.R. § 1.20(a) to Deposit Account No. 23-0925. Please credit Deposit Account No. 23-0925 with any overpayment of the above fee.

Respectfully submitted,

Dated: 9-15-08

By: 
D. Brent Kenady
Reg. No. 40045

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

Page 1 of 1

PATENT NO. : 7,183,220 B1
APPLICATION NO.: 09/677,478
DATED : February 27, 2007
INVENTOR(S) : Blalock, Guy T.; Becker, David S.;
Donohoe, Kevin G.

It is certified that errors appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Page 2 (56) References Cited (cont.) –

Please insert the following under U.S. Patent Documents:

--5,814,888	09/1998	Nishioka et al.
5,872,061	02/1999	Lee et al.
5,933,759	08/1999	Nguyen et al.
5,968,844	10/1999	Keller
6,010,967	10/2000	Donohoe et al.
6,127,278	10/2000	Wang et al.
6,258,728 B1	07/2001	Donohoe et al.
6,478,978 B1	11/2002	Allen, III
6,479,393 B1	11/2002	Allen, III--

Mailing Address of Sender:

D. Brent Kenady
Wells St. John P.S.
601 West First Avenue, Suite 1300
Spokane, WA 99201-3828

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1544SERIAL NO.
09/677,478LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Blalock et al.FILING DATE
October 2, 2000GROUP
1765

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
LV	AA	6,479,393 B1	11/12/02	Allen, III			
	AB	6,478,978 B1	11/12/02	Allen, III			
	AC	5,872,061	02/16/99	Lee et al.			
	AD	5,814,888	09/29/98	Nishioka et al.			
	AE	6,258,728 B1	07/10/01	Donohoe et al.			
LV	AF	6,010,967	01/04/00	Donohoe et al.			
	AG						
	AH						
	AI						
	AJ						
	AK						

COPY

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AR		
	AS		
	AT		

EXAMINER

LAN VINH

DATE CONSIDERED

3/14/2003

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

EV182657955

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/677,478
Filing Date October 2, 2000
Inventor Guy T. Blalock et al.
Assignee Micron Technology, Inc.
Group Art Unit 1765
Examiner L. Vinh
Attorney's Docket No. MI22-1544
Title: Plasma Etching Methods

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References – See Attached Form PTO-1449

The Examiner's attention is directed to the references which are listed on the attached Form PTO-1449, copies of which are attached. No admission is made regarding whether all the submitted references are prior art.

Citation of the referenced art is respectfully requested.

Respectfully submitted,

Dated: 12-30-02

COPY

By: _____

D. Brent Kenady
Reg. No. 40,045

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1544		SERIAL NO. 09/677,478	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Black et al.			
				FILING DATE October 2, 2000		GROUP 1765	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,479,393 B1	11/12/02	Allen, III			
	AB	6,478,978 B1	11/12/02	Allen, III			
	AC	5,872,061	02/16/99	Lee et al.			
	AD	5,814,888	09/29/98	Nishioka et al.			
	AE	6,258,728 B1	07/10/01	Donohoe et al.			
	AF	6,010,967	01/04/00	Donohoe et al.			
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER				DATE CONSIDERED			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1544SERIAL NO.
09/677,478LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Guy T. Blalock et al.FILING DATE
October 2, 2000GROUP
1765

U.S. PATENT DOCUMENTS

Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,868,853	2-9-99	Chen et al.			
	AB	6,136,211	10-24-00	Qian et al.			
	AC	5,968,844	10-19-99	Keller			
	AD	6,127,278	10-3-00	Want et al.			
	AE	5,933,759	8-3-99	Nguyen et al.			
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

COPY

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AM						
	AN						
	AO						
	AP						
	AQ						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AR		
	AS		
	AT		

EXAMINER

LAN VINH

DATE CONSIDERED

3/15/2002

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

RECEIVED
JAN 28 2002
TC 1700

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/677,478
Filing Date October 2, 2000
Inventor Guy T. Blalock et al.
Assignee Micron Technology, Inc.
Group Art Unit 1765
Examiner L. Vinh
Attorney's Docket No. MI22-1544
Title: Plasma Etching Methods

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -See Attached Form PTO-1449

The Examiner's attention is directed to the references which are listed on the attached Form PTO-1449, copies of which are attached. No admission is made regarding whether all the submitted references are prior art.

Citation of the referenced art is respectfully requested.

This Information Disclosure Statement is being filed within three months of the filing date of the application or before the mailing date of a first Office Action, whichever occurs last. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this information disclosure statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925. Please credit Deposit Account No. 23-0925 with any overpayment of the above fee.

Dated: Oct 19, 2001

By: Bernard Berman

Bernard Berman
Reg. No. 37,279

Respectfully submitted,

COPY

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1544SERIAL NO
09/677,478LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Guy T. Blalock et al.FILING DATE
October 2, 2000GROUP
1765

U.S. PATENT DOCUMENTS

Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	5,868,853	2-9-99	Chen et al.			
AB	6,136,211	10-24-00	Qian et al.			
AC	5,968,844	10-19-99	Keller			
AD	6,127,278	10-3-00	Want et al.			
AE	5,933,759	8-3-99	Nguyen et al.			
AF						
AG						
AH						
AI						
AJ						
AK						
AL						

COPY

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
AM							
AN							
AO							
AP							
AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AR		
AS		
AT		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.